

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BUSTA ET AL.	
		Examiner Kallambella Vijayakumar	Art Unit 1751	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,599,749	02-1997	Hattori, Atsuo	216/11
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.